Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/789,503	LILLE, JEFFREY S.	
Examiner	Art Unit	
Paul D. Kim	3729	

SEARCHED				
Class	Subclass	Date	Examiner	
29	603.07 603.1 603.12 603.16 851	12/6/2005	PK	
360	234.5			
	235.8			
264	434			
438	3			
216	22,39,41	V		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
Reviewed Parent Application 10/047,229 (US PAT. 6,725,526)	12/6/2005	PK
Text Search EAST/NPL (IEEE)	12/6/2005	PK
Updated Text Search EAST	10/17/2006	PK